

# Infrared Detectors for SNAP

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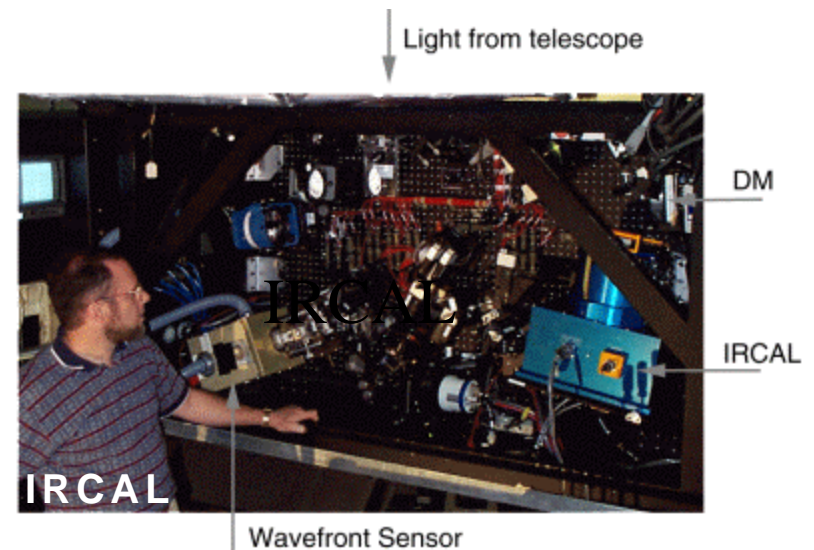
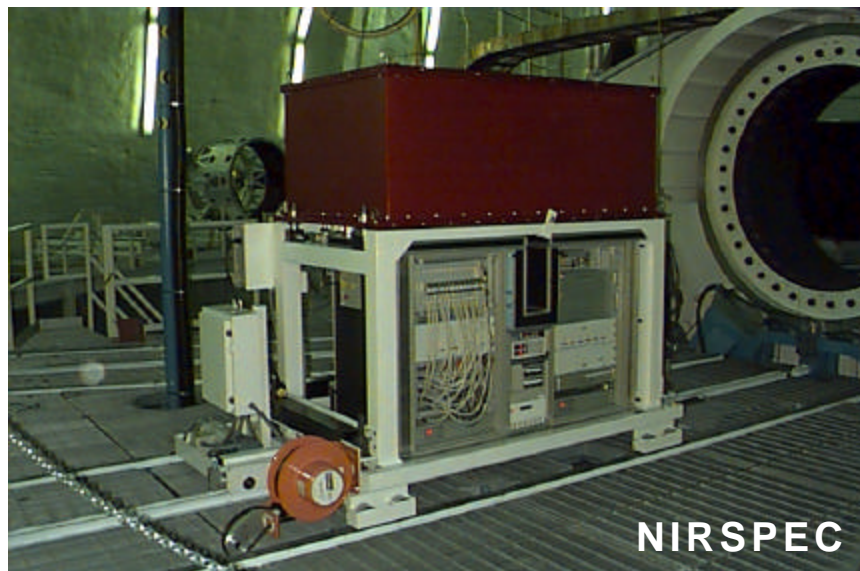
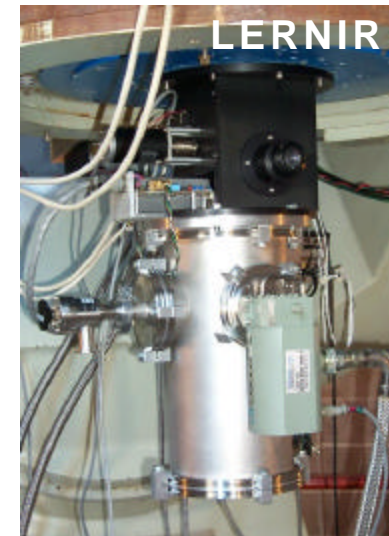


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# Infrared HgCdTe Detectors for SNAP



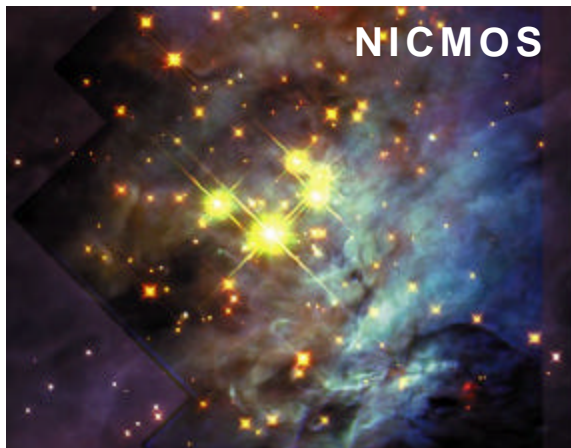
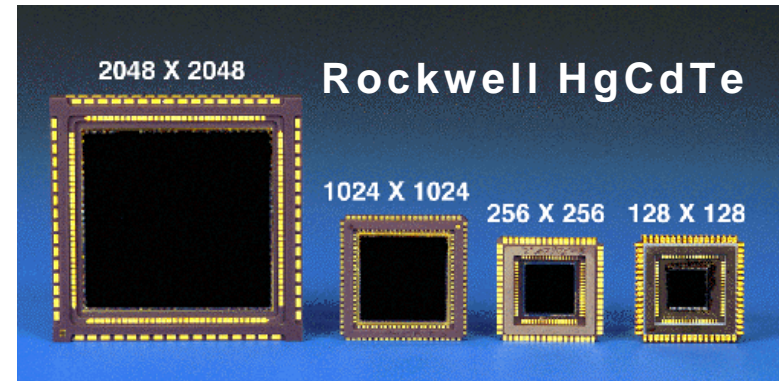
- Extensive Berkeley experience with state-of-the-art IR astronomy detector arrays
  - LERNIR
    - Leuschner Near Infrared Camera 256x256 HgCdTe PICNIC
  - IRCAL
    - Lick AO camera 256x256 HgCdTe PICNIC
  - NIRSPEC
    - Keck cryogenic echelle with 1024 x 1024 InSb ALLADIN



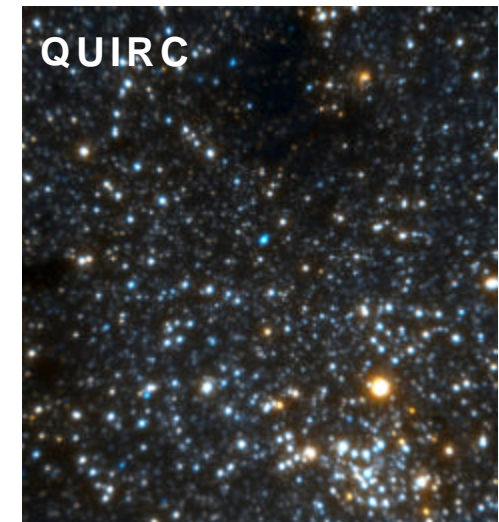
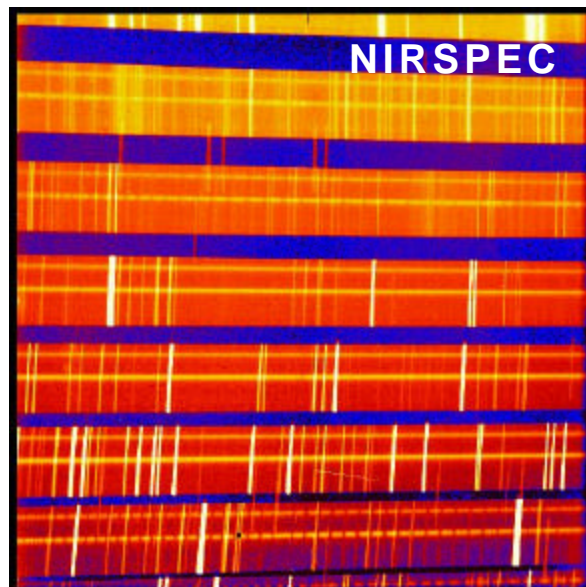
# Explosive growth in IR detector technology



- **Revolutionary advances in near IR (1-5 micron) detectors**
  - Growth from 58 x 62 to 2048 x 2048 pixel focal plane arrays in last decade
  - High performance
    - Low read noise:  $< 10 e^-$  rms
    - Low dark current:  $< 0.1 e^-/s$
    - High QE:  $> 70\%$  1 -5 mm
- Proliferation of InSb & HgCdTe instruments
  - HST/NICMOS: 256 x 256 HgCdTe
  - Keck/NIRSPEC: 1024 x 1024 InSb
  - GEMINI/QUIRC: 1024 x 1024 HgCdTe



256 x 256

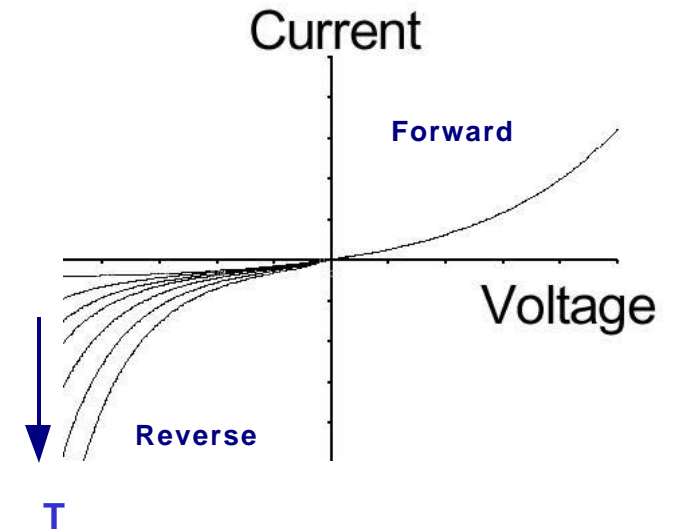


1024 x 1024

# Infrared Detector Options for Astronomy



- Common detectors are based on photovoltaic effect in a reverse biased pn diode
- Detector band gap determines operating temperature
  - Dark current due to thermally excited diffusion and generation-recombination has strong T dependence
  - IR detectors operate at lower temperatures than Si CCDs
  - Minimize cooling requirements by picking shortest cut-off wavelength compatible with science
- $\text{Hg}_{(1-x)}\text{Cd}_x\text{Te}$  --- x determines band gap



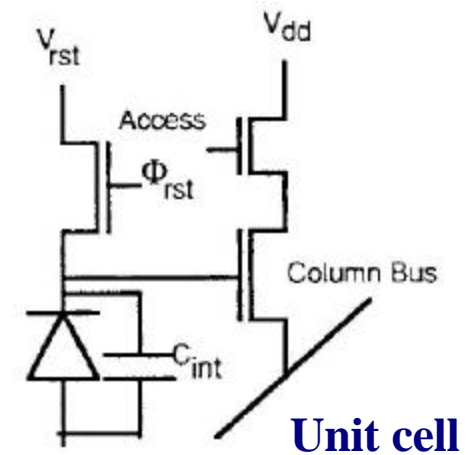
Material	Band Gap (mm)	Operating Temp (K)
Si	1.1	140 - 300
Ge	1.8	77
InSb	5.6	4 - 77
$\text{Hg}_{(1-x)}\text{Cd}_x\text{Te}$	< 20	20 - 300



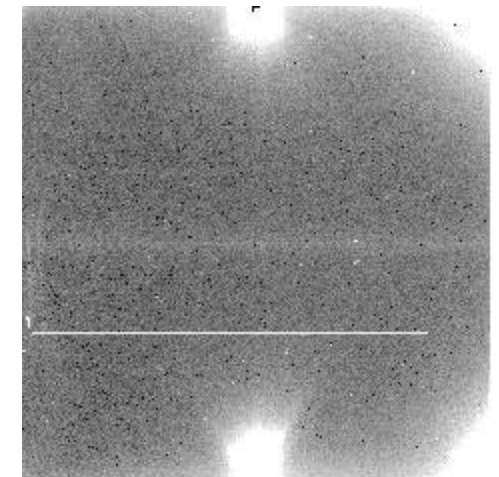
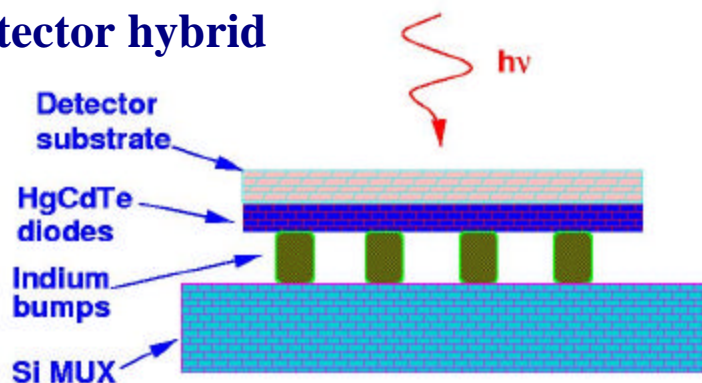
# Hybrid Focal Plane Array Architecture



- **Detector diodes bonded to a Si multiplexer for read out**
  - **Row & column shift registers allow sequential access to each pixel**
    - **Detector & readout circuit optimized separately**
    - **Multiple sampling**
    - **No charge transfer efficiency**
  - **Detector mechanically bonded to MUX**
    - **Thermal expansion mismatch effects**
  - **Special epitaxy technologies for growing diodes**
    - **PACE: Metal chemical vapor deposition of CdTe on sapphire followed by liquid epitaxy growth of HgCdTe**
    - **MBE: potential for improved performance**



## Detector hybrid



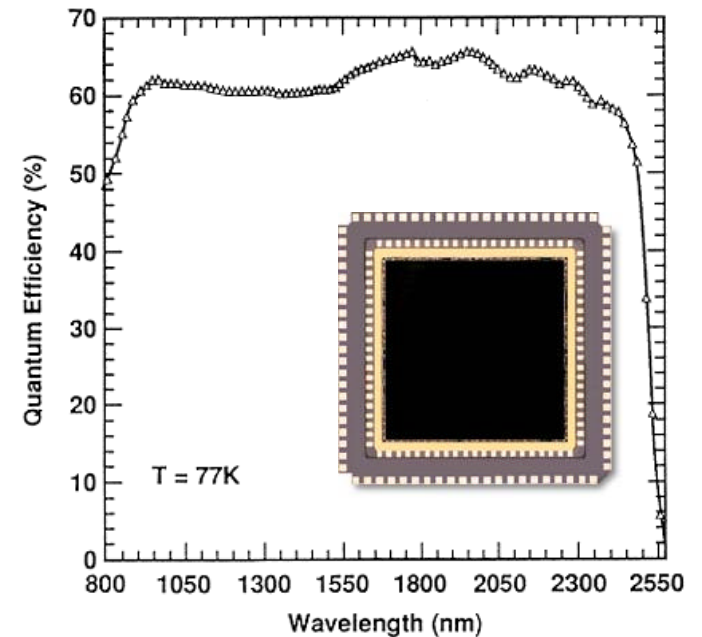
Hawaii-1 glow

# State-of-the-Art Large Format HgCdTe



- **Rockwell HAWAII family**
  - **1024 x 1024 HAWAII-1 2.5 mm PACE HgCdTe**
    - 18.5 mm pixel pitch
    - 25 devices delivered and in use
    - PACE technology
      - Dark current
      - Uniformity
      - Residual images
    - Read noise 3.5 e- rms achieved (10 e- rms CDS)
    - Dark current < 0.1 e- achieved at T ~ 60 K
    - Power < 2 mW
    - Average QE ~ 65%
    - Four-quadrant/four output MUX
      - Read noise
      - Amplifier glow
  - **2048 x 2048 HAWAII-2 2.5 mm PACE HgCdTe**
    - 18 micron pixels - 40 mm x 40 mm device
    - 4/8/16/32 readout MUX for improved output-FET glow
    - Improved MFT
    - Twenty fabricated
      - Devices delivered to UH, ESO, & SUBARU
  - **1024 x 1024 HAWAII-1 5 mm PACE HgCdTe**

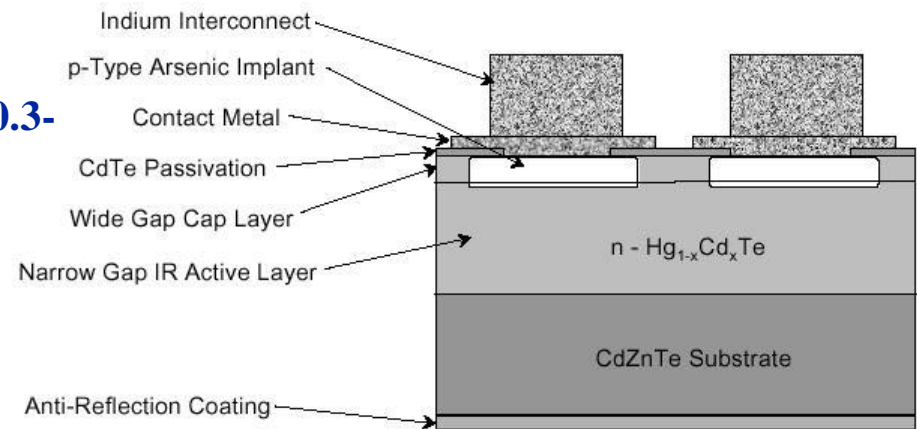
## HAWAII-1 QE



# HgCdTe Technology Development



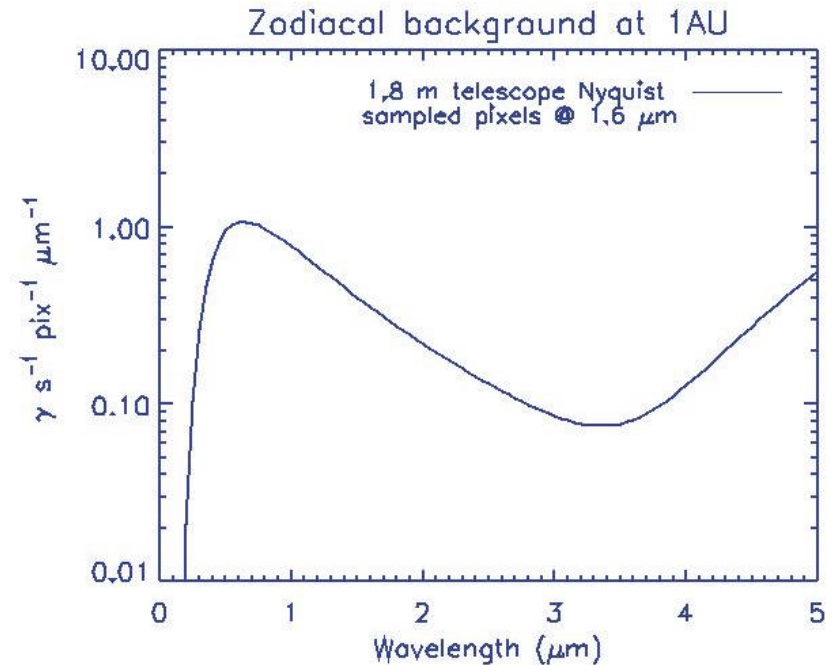
- **Molecular beam epitaxy diode fabrication**
  - HgCdTe is grown by MBE on CdZnTe
    - Improved lattice match between HgCdTe & CdZnTe vs.  $\text{Al}_2\text{O}_3$
    - Fewer lattice defects - dark current approaching  $0.001 \text{ e}^-/\text{s}$
    - Dramatically reduced residual images 0.3-0.5% after saturation
      - None detectable after one read
    - Better uniformity
    - Worse CTE mismatch to CdZnTe
    - CdZnTe available in small wafers
      - One device 2048 x 2048 per wafer
    - Driven by NGST 5.0 mm program
- **Multiplexer design**
  - HAWAII-1R MUX
    - Reference pixels
    - Output FET glow mitigation
    - Mated to 1.7, 2.5 or 5.0 mm HgCdTe
- **Short wavelength cut-off HgCdTe**
  - QE limited by AR coating



# Shortwave HgCdTe Arrays for SNAP



- **Short wave cut-off (< 2  $\mu\text{m}$ ) HgCdTe can yield low dark current at CCD operating temperature**
  - Option for CCDs & IR arrays to share 140-150 K thermal environment
  - Dark current < 0.1 e<sup>-</sup>/s for zodi-limited operation requires MBE
- **No commercial short wave HgCdTe**
- **HgCdTe development programs**
  - **HST/WFC-3 1.7  $\mu\text{m}$  MBE HgCdTe**
    - 1024 x 1024
    - HAWAII-1R MUX
  - **VLT/NIRMOS 1.9  $\mu\text{m}$  MBE HgCdTe**
    - 2048 x 2028
    - Four devices
    - HAWAII-2 MUX



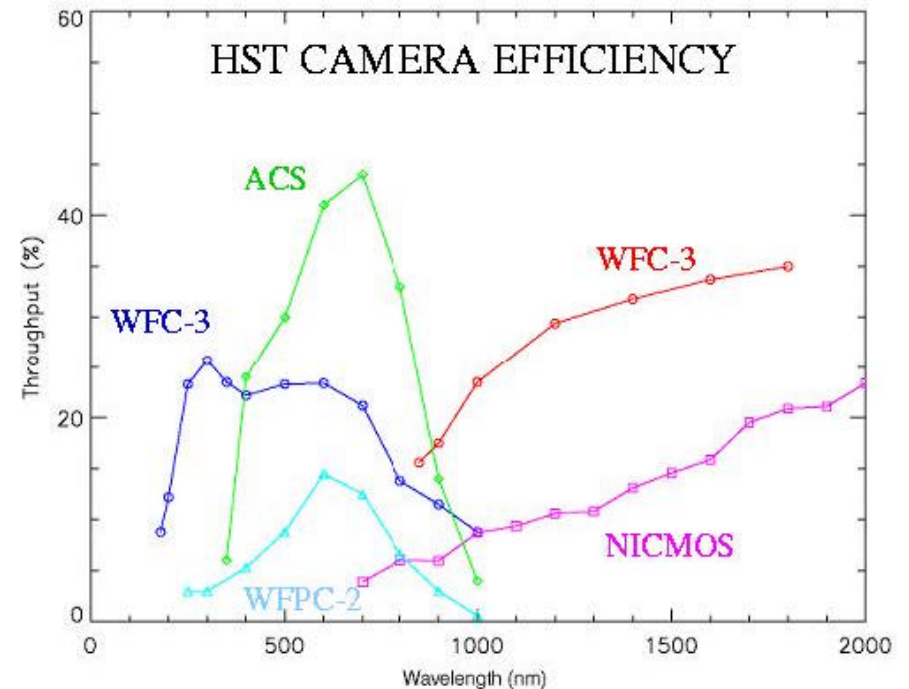
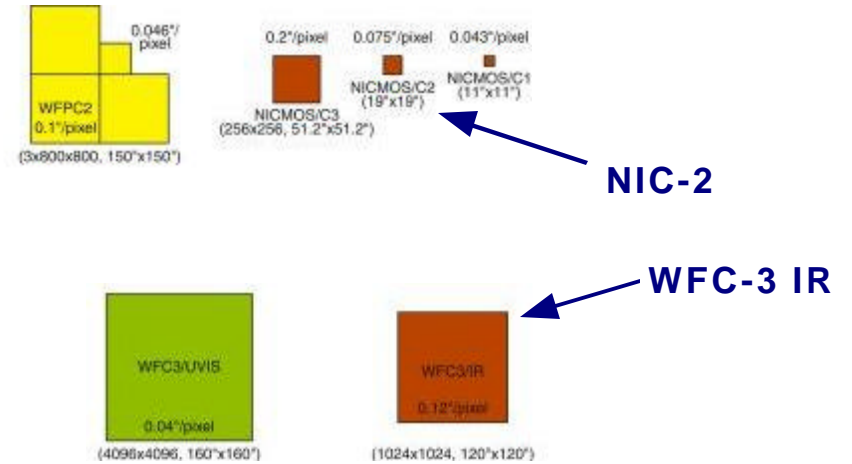


# Shortwave HgCdTe Development



- *Hubble Space Telescope Wide Field Camera 3*

- WFC-3 replaces WFPC-2
  - CCDs & IR HgCdTe array
  - Ready for flight July 2003
- 1.7 mm cut off
- 18 mm pixel
- 1024 x 1024 format
  - Hawaii-1R MUX
- Dark current consistent with thermoelectric cooling
  - < 0.5 e/s at 150 K
  - < 0.05 e/s at 140 K
- Expected QE > 50% 0.9-1.7 mm
- Individual diodes show good QE
  - Effective CdZnTe AR coating
  - No hybrid device with simultaneous good dark current & QE



# Conclusion & Recommendations



- **Clear technology choice for the foreseeable future**
  - **HgCdTe**
    - Short wave cut off HgCdTe on MBE is within reach
    - Zodi limited performance
    - Compatible with Si CCD thermal environment
    - Leverage national (NASA HST/NGST) and international development programs (ESO VLT )
  - **Ge, InSb, InGaAs, PtSi**
    - Immature technology
    - Significant performance penalty
    - Incompatible with Si CCD thermal environment
- **Rockwell has mastered component technologies for large format, high performance HgCdTe**
  - Satisfies requirements of baseline IR camera
  - HST/WFC-3 devices represent the state-of-the-art for IR flight detectors
    - Goddard SFC takes delivery of science grade devices 1/31/2001
    - Select flight array Fall 2001
- **Evaluate performance, cost, & risk trade of**
  - **2048 x 2048**
  - Evolution of MUX from HAWAII-1/2/1R to Hawaii-2R MUX
  - Buttable architecture to reach 4096 x 4096